

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	177	tube with recognition with pattern	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:25
L2	181	tube with recognition with (pattern or waveform)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:27
L3	29	tube near4 recognition with (pattern or waveform)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:30
L4	322	tube near4 recognition	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:33
L5	6	("3202761").URPN.	USPAT	OR	OFF	2007/07/23 12:32
L6	47	tube near4 recognition and camera	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:34
L7	15	tube near4 recognition and camera and inspect\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:40

EAST Search History

L8	868	tube near4 inspect\$4 and camera	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:41
L9	188	tube near4 inspect\$4 and camera and (opening with tube)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:42
L10	30	tube near4 inspect\$4 and camera with (opening with tube)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 13:04
L11	68	tube near4 inspect\$4 and cameras with tube	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/23 13:52
L12	87	382/142.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 13:59

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

 Search Results[BROWSE](#)[SEARCH](#)[IEEE Xplore GUIDE](#)

Results for "((((tube <near> inspect*)<in>metadata))<and>('cameras'<in>metadata))"

[e-mail](#)

Your search matched 2 of 111 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by **Relevance** in **Descending** order.» **Search Options**[View Session History](#)[New Search](#)**Modify Search** Check to search only within this results setDisplay Format: **Citation** **Citation & Abstract**» **Key****IEEE JNL** IEEE Journal or Magazine**IET JNL** IET Journal or Magazine**IEEE CNF** IEEE Conference Proceeding**IET CNF** IET Conference Proceeding**IEEE STD** IEEE Standard [Select All](#) [Deselect All](#) 1. **Inspection of continuously moving metallic tubes by artificial vision: model and results**Truchetet, F.; Jender, H.; Lew-Yan-Voon, L.F.C.; [Industrial Electronics, Control and Instrumentation, 1994. IECON '94., 20th International Conference on](#)Volume 2, 5-9 Sept. 1994 Page(s):749 - 754 vol.2
Digital Object Identifier 10.1109/IECON.1994.397879[AbstractPlus](#) | Full Text: [PDF\(356 KB\)](#) [IEEE CNF Rights and Permissions](#) 2. **Using computer vision for the automatic inspection and alignment of tele**Yerem, G.C.; Koch, D.B.; [SoutheastCon, 2002. Proceedings IEEE](#)5-7 April 2002 Page(s):67 - 72
Digital Object Identifier 10.1109/2002.995560[AbstractPlus](#) | Full Text: [PDF\(524 KB\)](#) [IEEE CNF Rights and Permissions](#)[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2006 IEEE -

Indexed by
 **Inspec**